Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	-
10/643,404	TANAKA ET AL.	
Examiner	Art Unit	
Brian S. Kwon	1614	

SEARCHED						
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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